

Search Notes

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10/616,492

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	58	2/28/2006	BT
216	63	2/28/2006	BT
216	68	2/28/2006	BT
216	74	2/28/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	2/28/2006	BT